



The Testcenter facility 'LoRa® Test Lab' within IMST GmbH is recognized by the LoRa™ Alliance for testing in accordance to the LoRaWAN™ Specification V1.0.4

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# **Report for Certification by Similarity according to LoRaWAN™ V1.0.4**

for the Device

**“LSN50v2“**

for the Customer

**“Shenzhen Dragino Techno-logy De-  
velopment co. LTD”**

Jens Lerner  
Yavuz Turan

27<sup>th</sup> September, 2021

## Administrative Summary

Location: IMST GmbH, Test Centre, Kamp-Lintfort, Germany

Responsible Test Engineer: Yavuz Turan, Jens Lerner

Subject: Test of Conformance to LoRaWAN™ Specification V1.0.4

Company and Contact Information:

Shenzhen Dragino Technology Development co. LTD

Edwin Chen

No.8 CaiYunRoad, LongCheng Street, LongGang District

518116, Shenzhen

China

Checked Device: LSN50v2

Hardware version: LSN50v2

Firmware version: LSN50v2 v1.8.0

Type and Version of used Stack: own

Original End-device identifier: LST Module

LoRa Device Class: A

LoRaWAN Specification version: V1.0.4

Certification requirements: LoRa End Device Certification by Similarity V1.1

Frequency band(s): 868 MHz

Type of Certification by Similarity:

Case 1: End-device certification using a certified module

Variant device differences to the referenced certified device:

- Same LoRa transceiver
- Same LoRa protocol SW version
- Same MCU Core
- Same Clock design and implementation

Brief description of the differences between the primary and the variant device

They are of same LoRaWAN Module

Date: 27<sup>th</sup> September, 2021

The Test Report, No. 6210800 has the following conclusion:

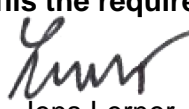
**The device fulfils the requirements.**

Responsibility:

  
Yavuz Turan

Test Engineer

Approved:

  
Jens Lerner

Quality Engineer

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